

APPLIED SURFACE SCIENCE



applied surface science

A JOURNAL DEVOTED TO APPLIED PHYSICS
AND CHEMISTRY OF SURFACES AND INTERFACES

Editors:

D.E. Aspnes, Raleigh, NC, USA
F.H.P.M. Habraken, Utrecht, The Netherlands
S. Ushioda, Sendai, Japan

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A journal devoted to applied physics and chemistry of surfaces and interfaces

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Editors

Professor D.E. Aspnes
North Carolina State University
P.O. Box 8202
Raleigh, NC 27695-8202
USA

Fax: +1 919 515 1333
E-mail:
aspnes@unity.ncsu.edu

Professor F.H.P.M. Habraken
Debye Institute
Utrecht University
P.O. Box 80.000
3508 TA Utrecht
The Netherlands

Fax: +31-30-2535787
E-mail: f.h.p.m.habraken@phys.uu.nl

Professor S. Ushioda
Research Institute of Electrical Communication
Tohoku University, 2-1-1 Katahira, Aoba-ku
Sendai 980-8577
Japan

Fax: +81 22 217 4736
E-mail: ushioda@ushioda.riec.tohoku.ac.jp

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Applied Surface Science is concerned with applied physics and chemistry of surfaces and interfaces and with the atomistic description of processing, modification and characterization of surfaces, interfaces and thin films. These include growth and epitaxy, oxidation, reactivity as well as surface modification by directed energy deposition (lasers, ions or electron beams) or other techniques (i.e. plasma etching). Important areas in the field are electronic materials (i.e. semiconductors, organic films, ceramics) and chemical processes at surfaces (catalysis, corrosion, reactivity).

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